Supporting Information for

Investigation of Laser Induced Graphene (LIG) on a Flexible Substrate and its Functionalization with Metal-doping for Gas Sensing Application

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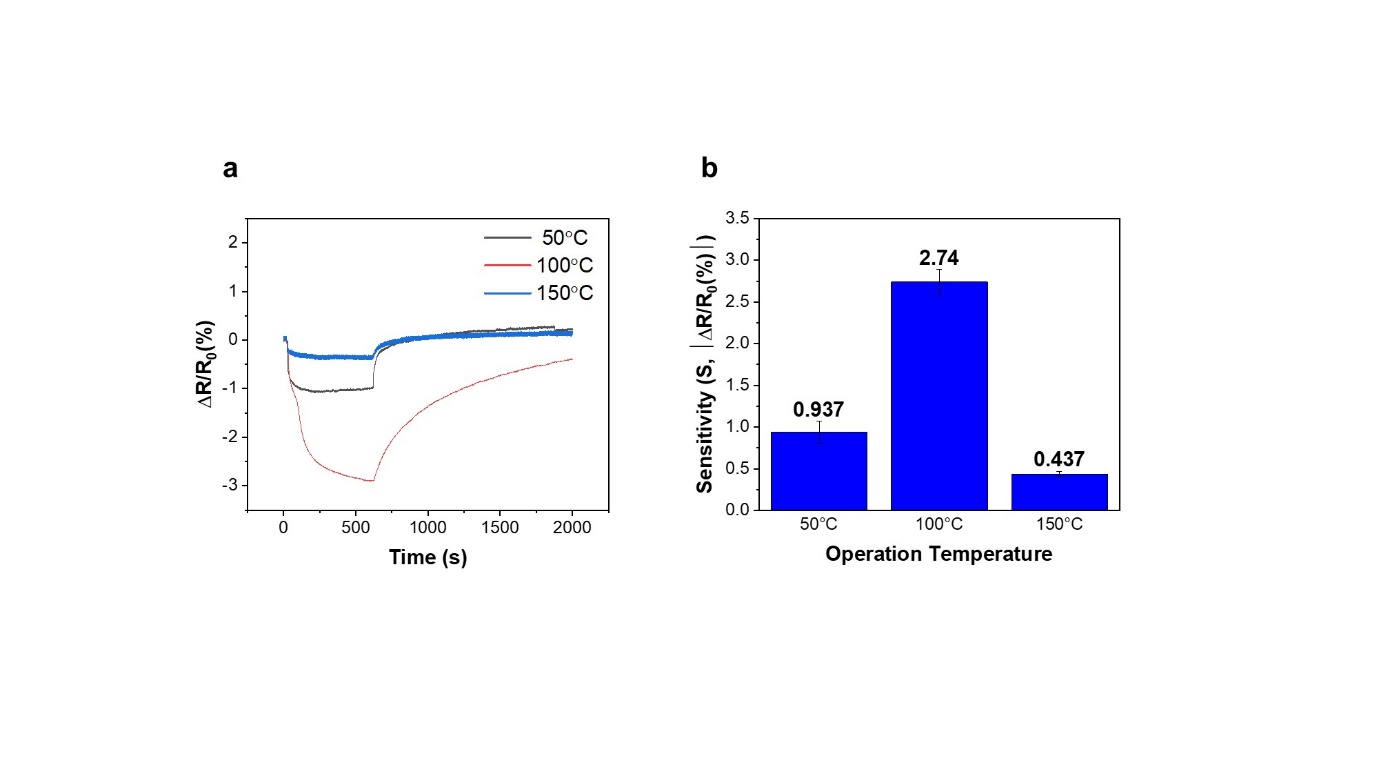
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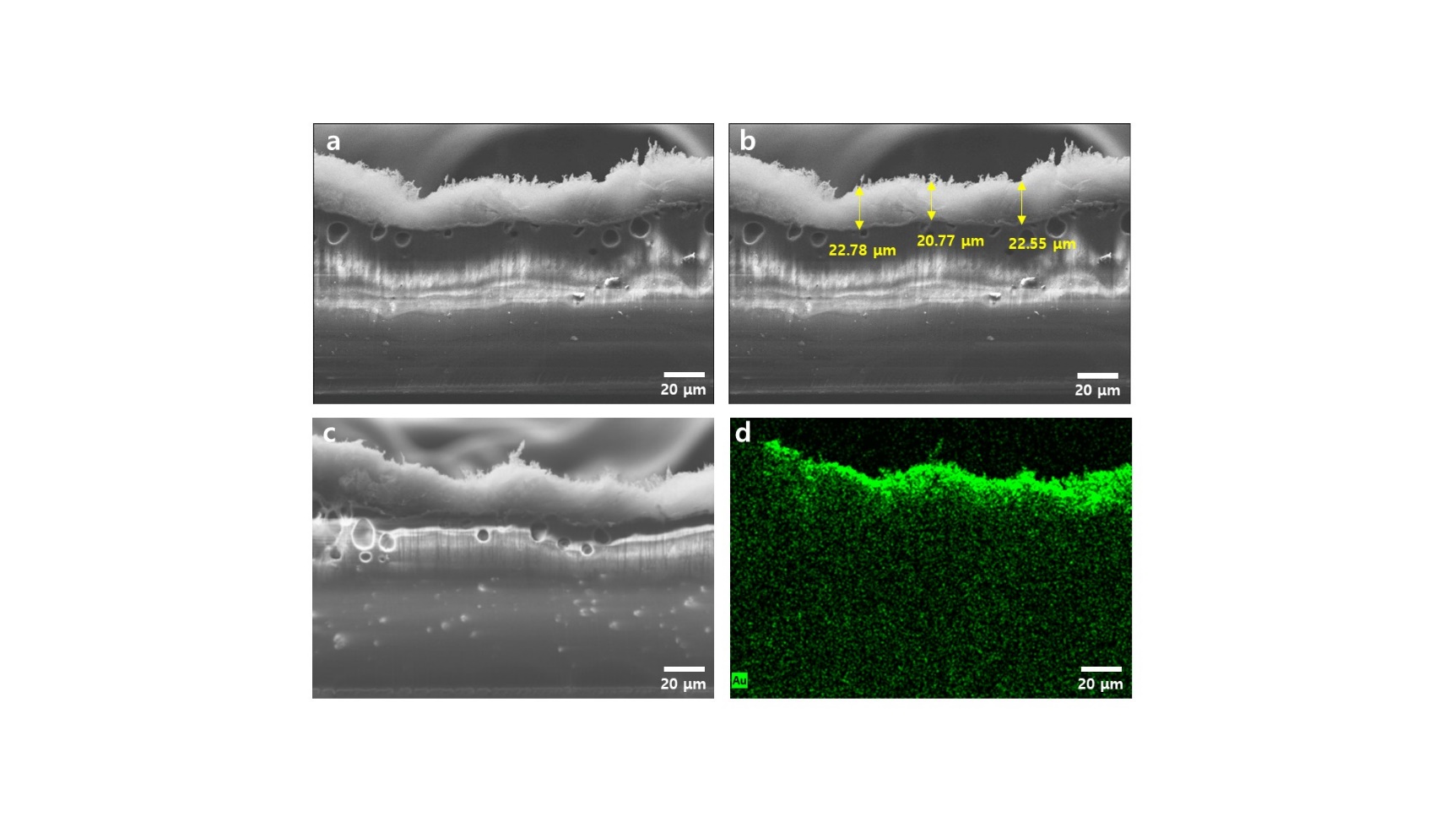
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**Table S1.** XPS quantification results for the P- and M-LIG devices.

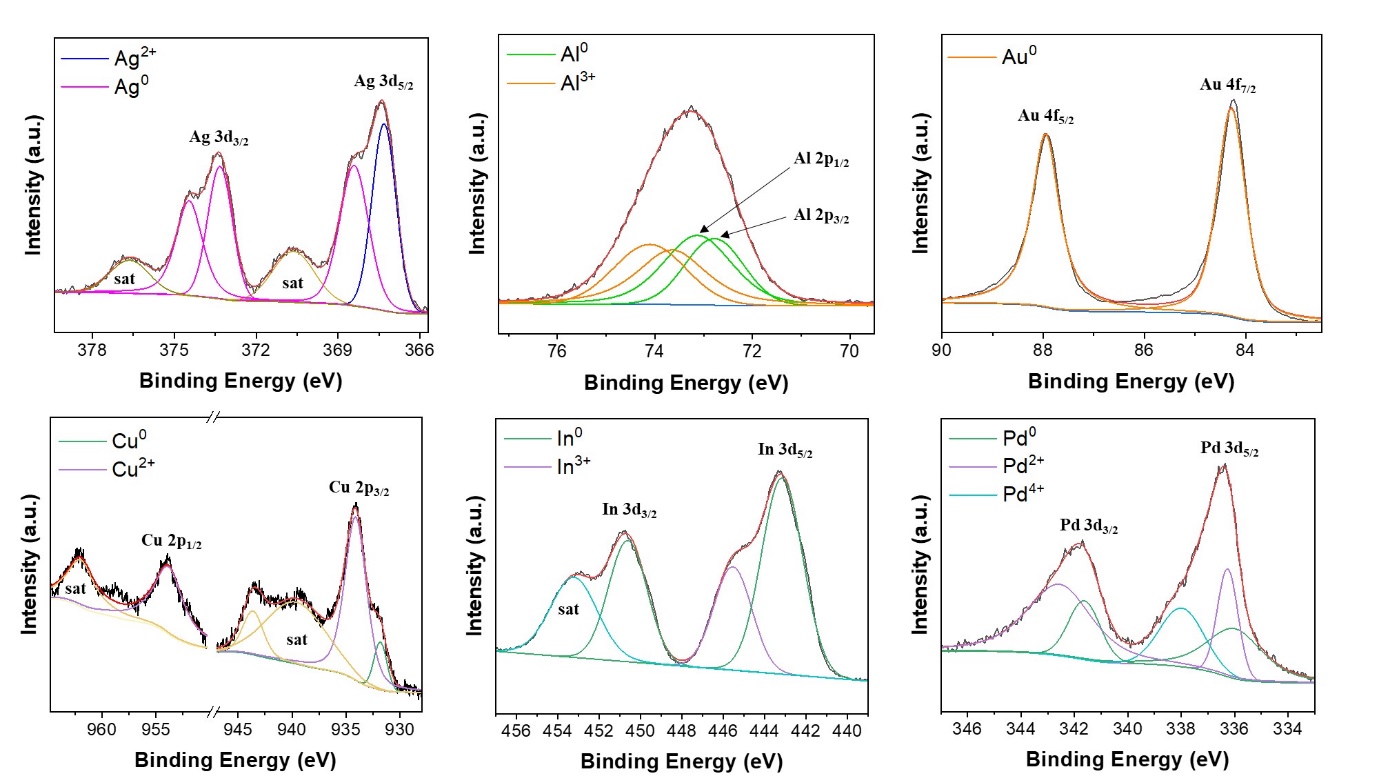
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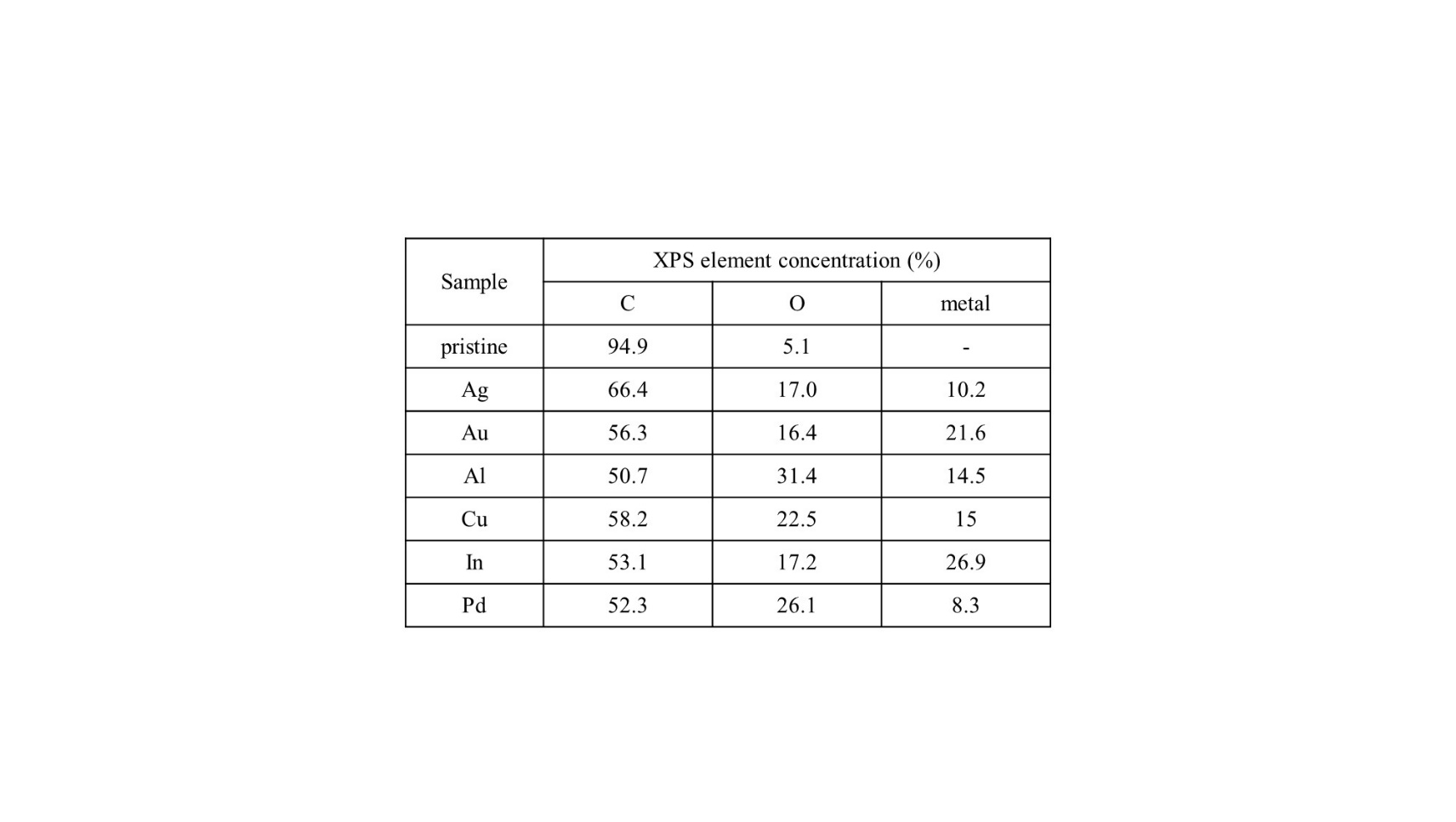
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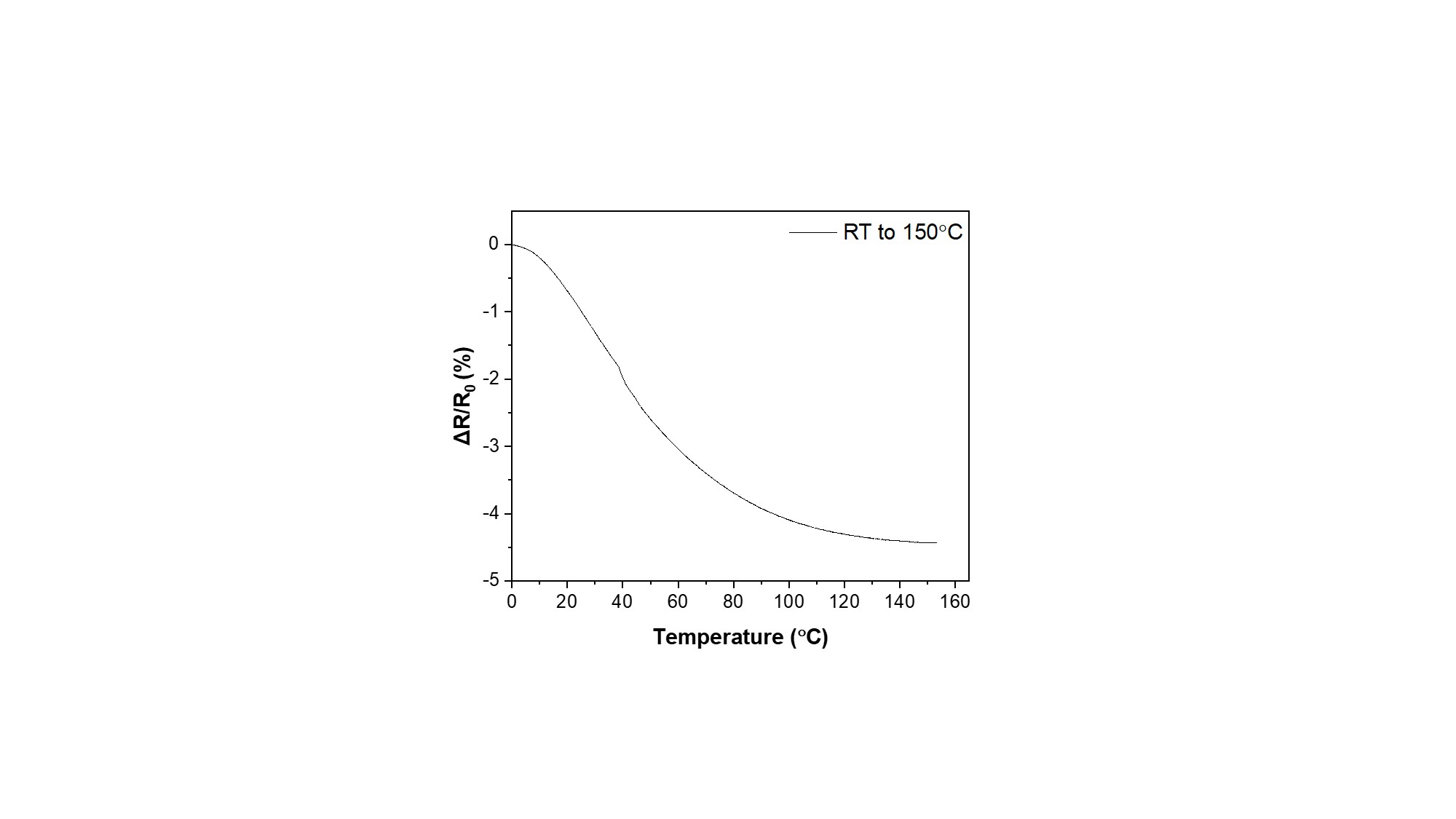
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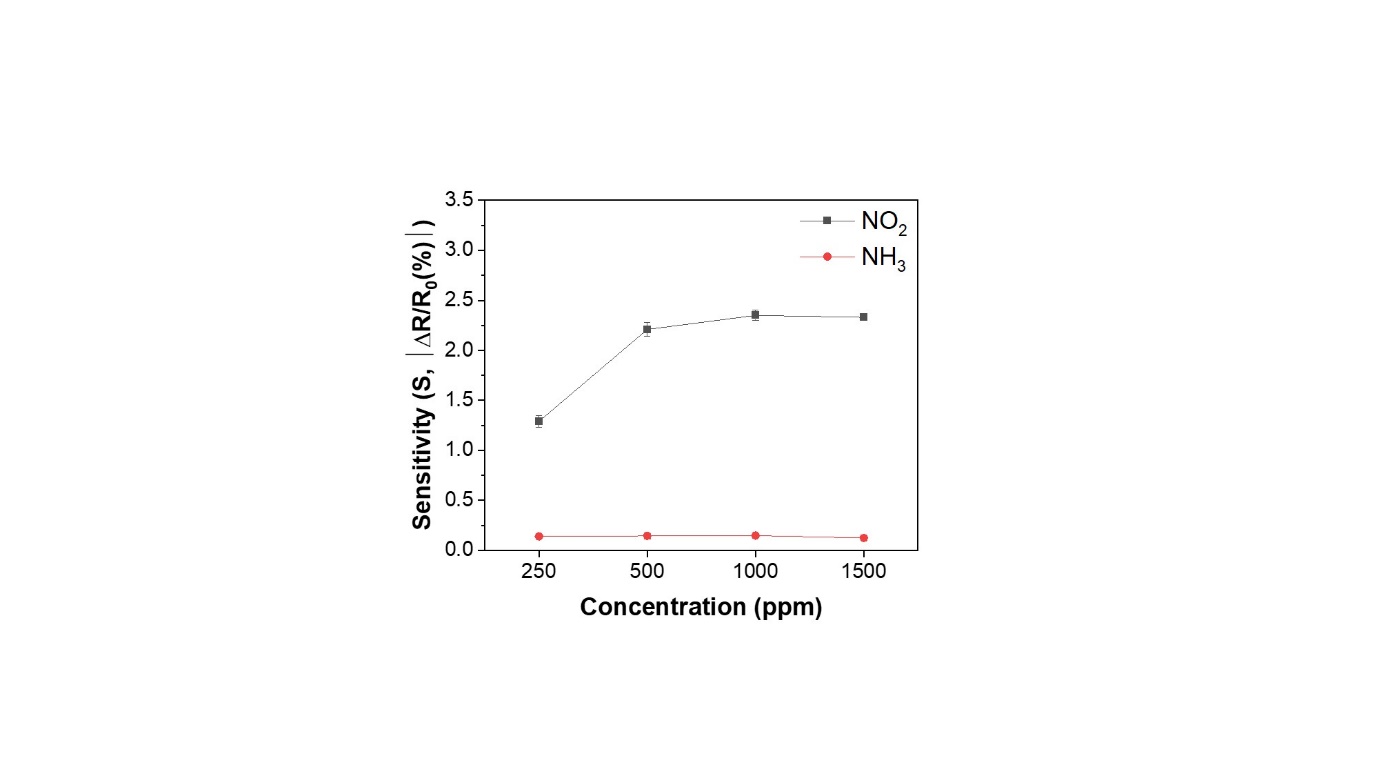
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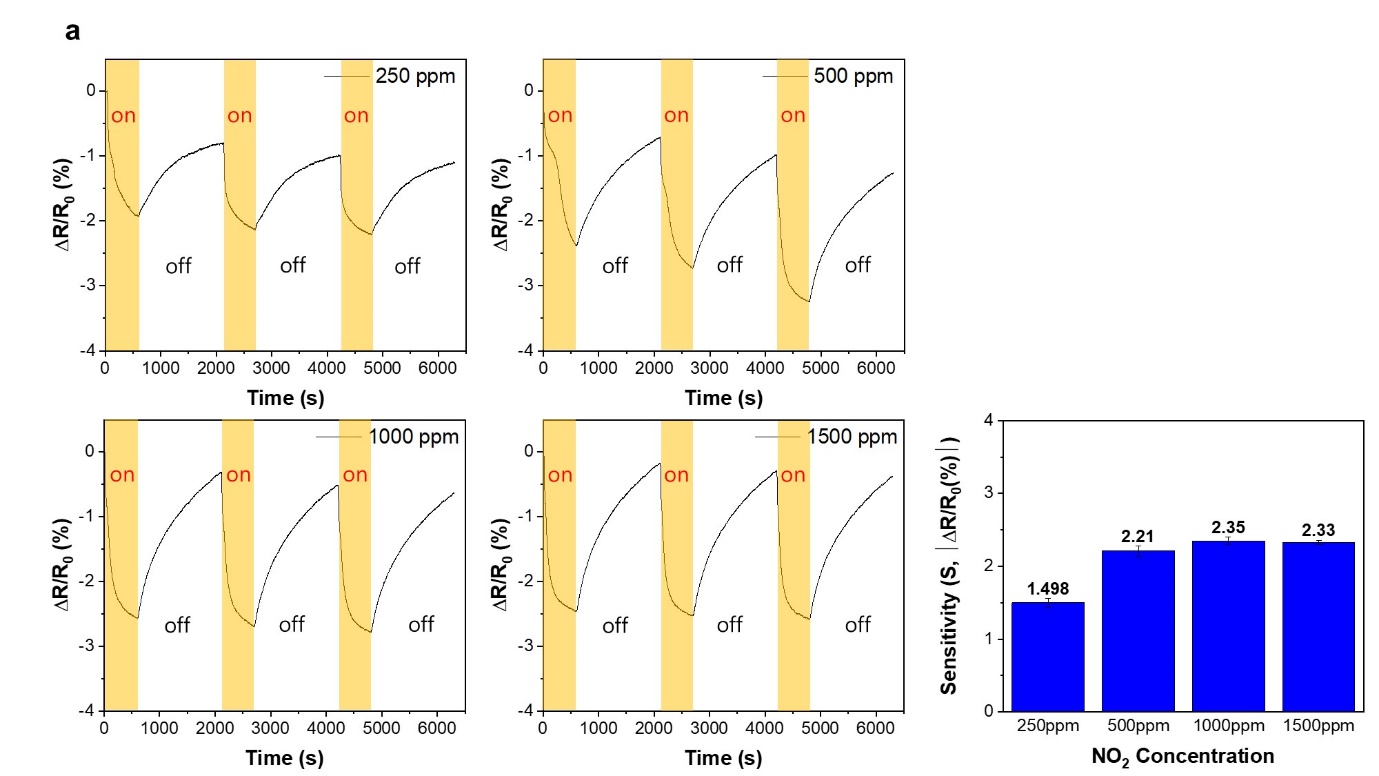
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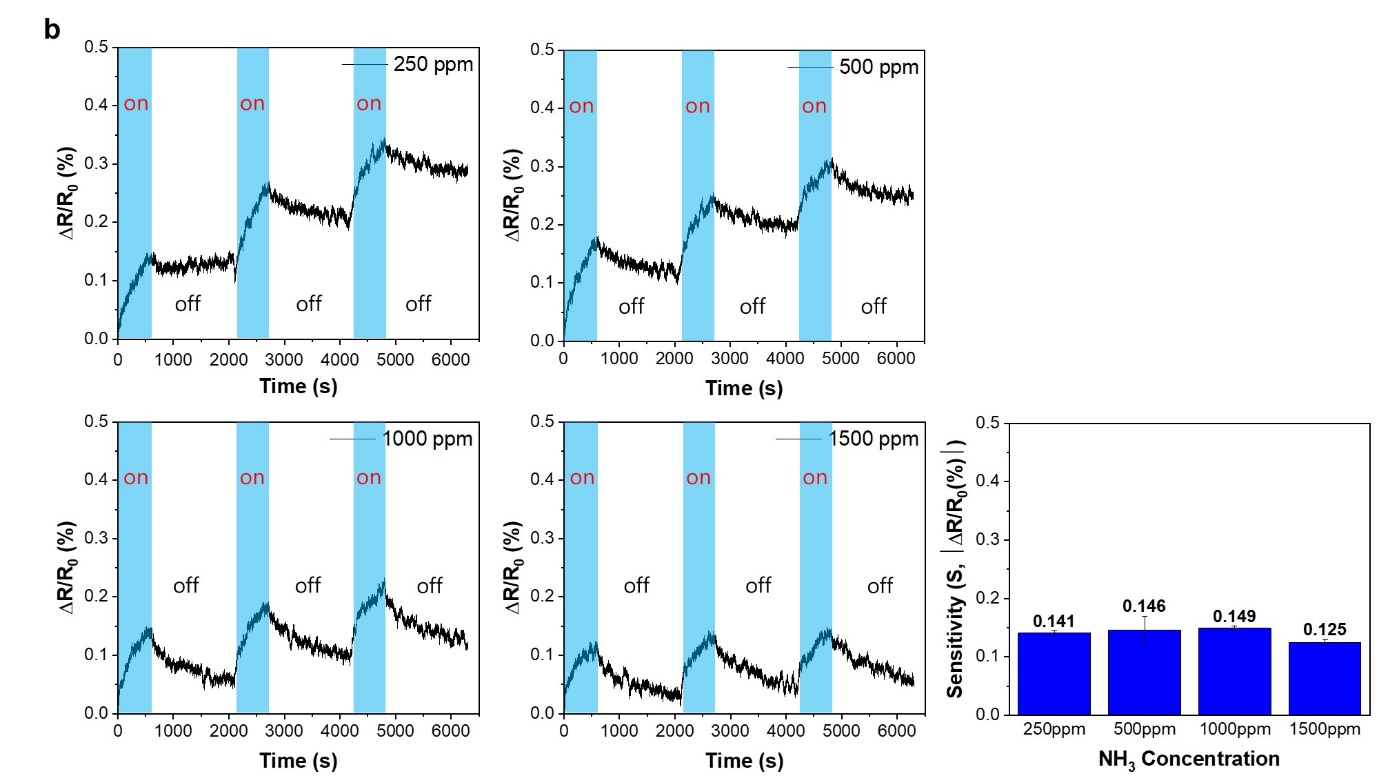
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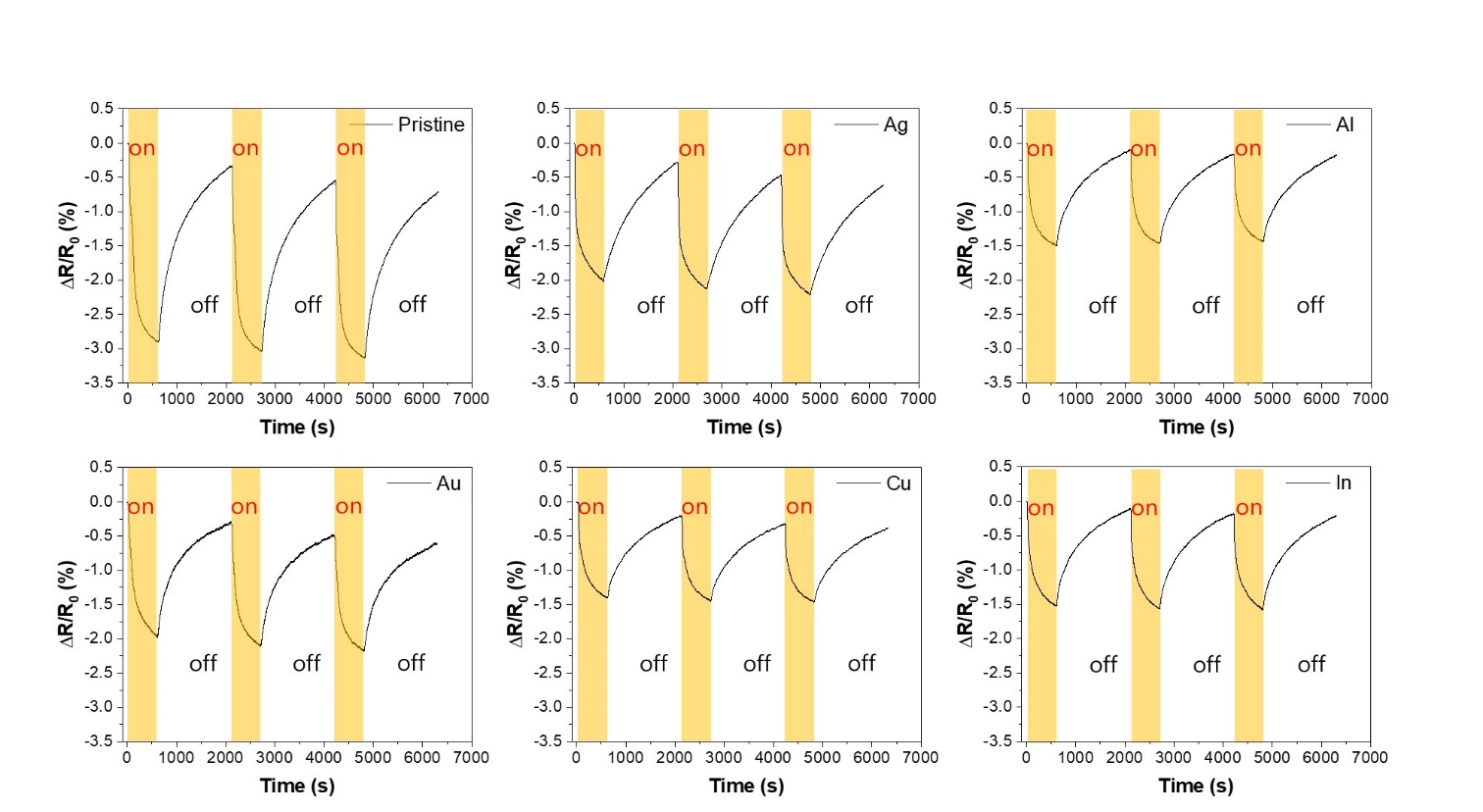
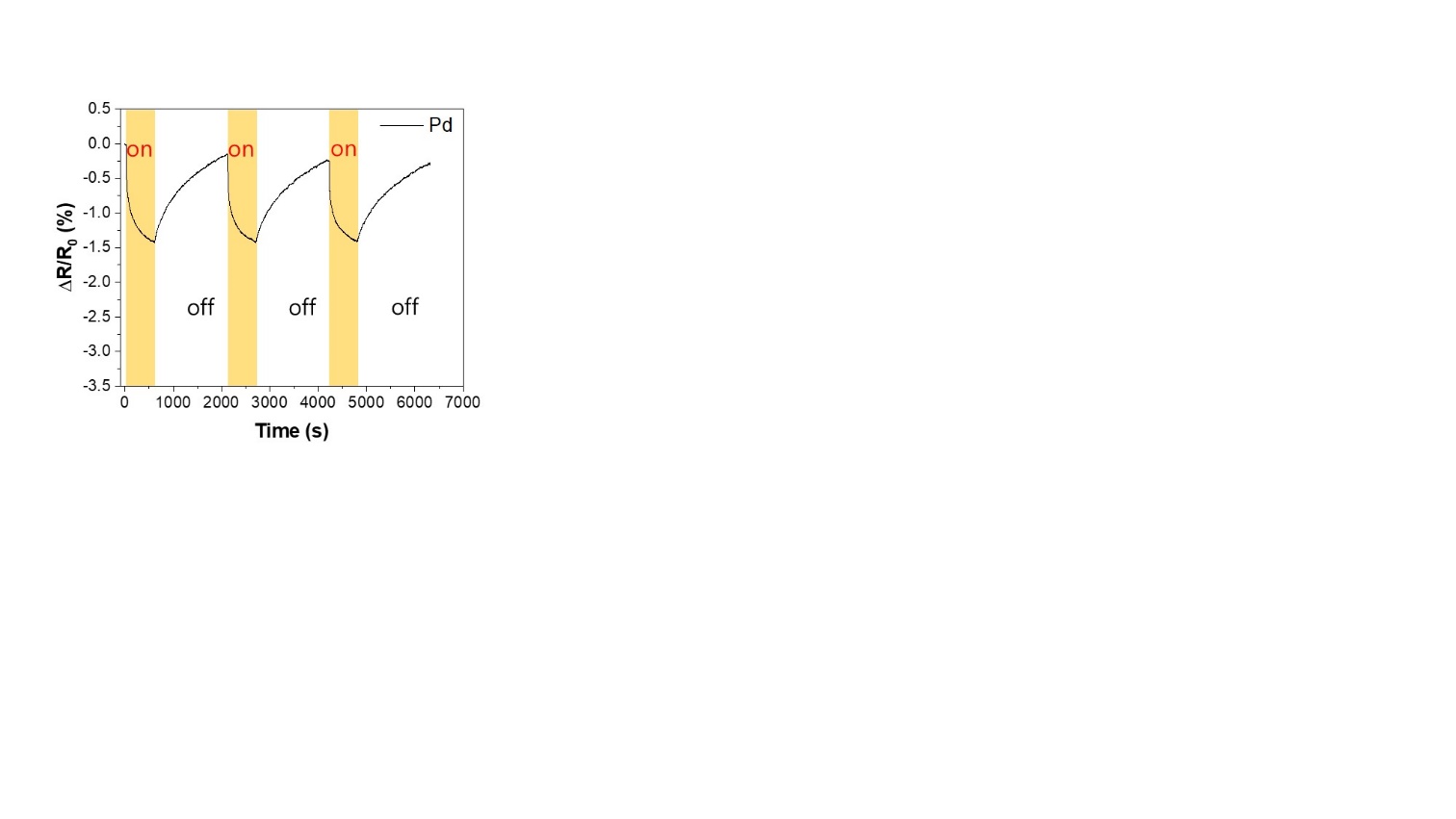
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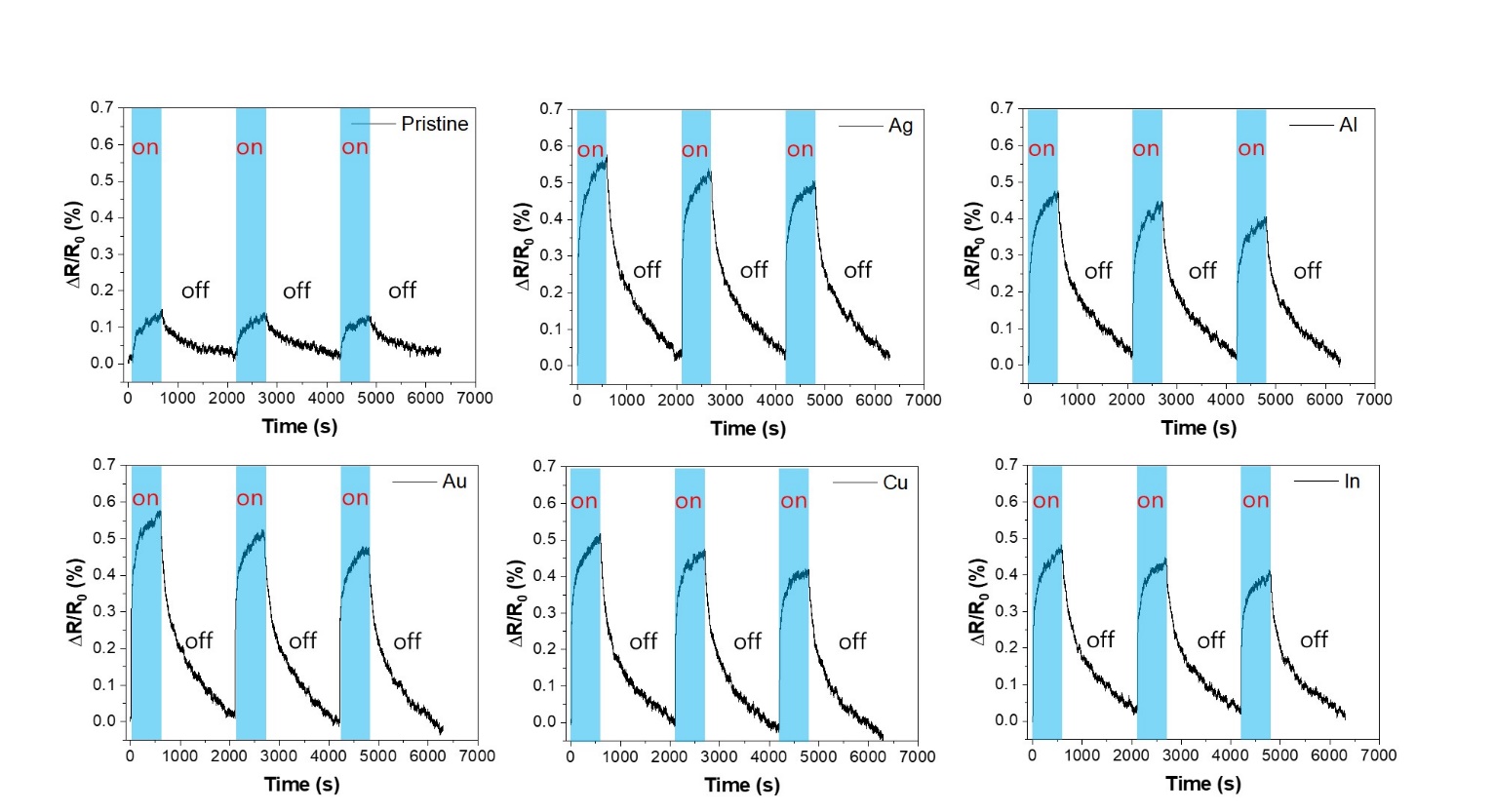
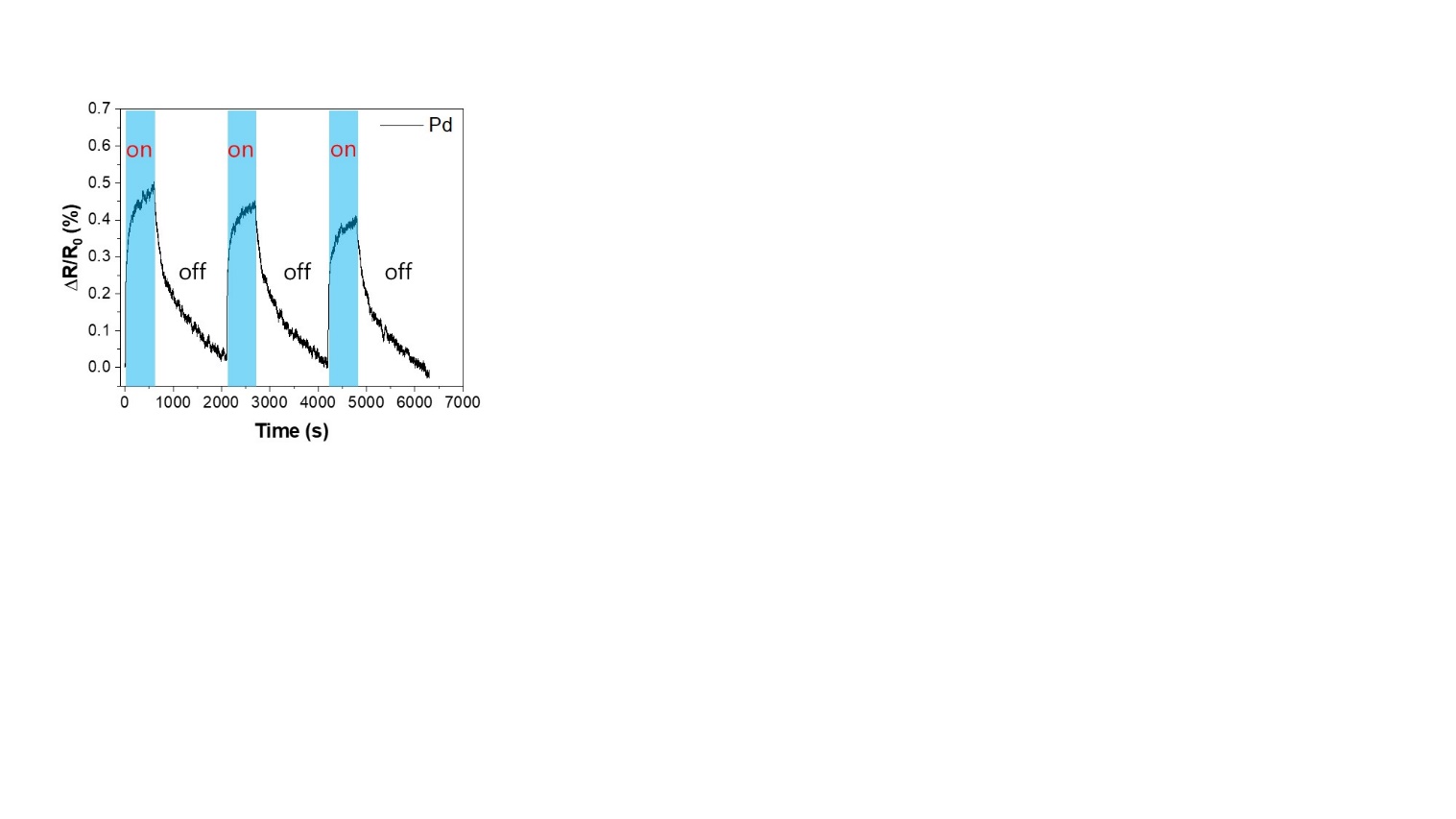
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